

Special Issue

Software Analysis and Testing for Large-Scale Software Systems

Message from the Guest Editors

This Special Issue aims to present the latest research and practices related to improving the dependability and quality of software systems. We solicit high-quality work describing original and unpublished results of theoretical, empirical, conceptual, and experimental research at any point in software quality assurance approaches. Topics of interest include, but are not limited to:

- Reliability, availability, and efficiency of software systems;
- Software testing, verification, and validation;
- Software configuration;
- Program analysis, debugging and comprehension;
- Information and software quality assurance;
- Fault tolerance for software reliability improvement;
- Software vulnerabilities;
- Mining software repositories and software analytics;
- Software maintenance and evolution;
- Benchmarking, tools, industrial applications, and empirical studies;
- AI for software quality assurance;
- Software quality assurance for AI.

Guest Editors

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Dr. Yan Lei

Dr. Zhouyang Jia

Deadline for manuscript submissions

closed (31 December 2023)



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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

Prof. Dr. Flavio Canavero

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